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					APPLICANT Mitsuyasu OHTA, et al.					
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	_			U.S. PATEN	T DOCUMENTS					
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Codez (# known)		Publication Date MM-DD-YYYY	Name of Patentee or Appli Document	Page Relev	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			
/CB/		us	US 5,258,985 11/02/1993		Spence et al.	Spence et al.				
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INITIALS CITE journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.										
/CB/		MO Chin Tsung., et al. " Self Diagnostic BIST Memory Design Scheme." IEEE, pp. 7-9, August 8, 1994								
/CB/		<u> </u>	WUNDERI	LICH et al. " Bit-Fli	pping BIST." IEEE, pp. 337-343	3, November	10, 1996			
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/Cynthia Britt/

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